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(74) Agents: RÖGGLA, Harald et al.; Philips Intellectual
Property & Standards, Triester Strasse 64, A-1101 Vienna
(AT).

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(71) Applicant (*for all designated States except US*): KONIN-
KLJKE PHILIPS ELECTRONICS N.V. [NL/NL];
Groenewoudseweg 1, NL-5621 BA Eindhoven (NL).

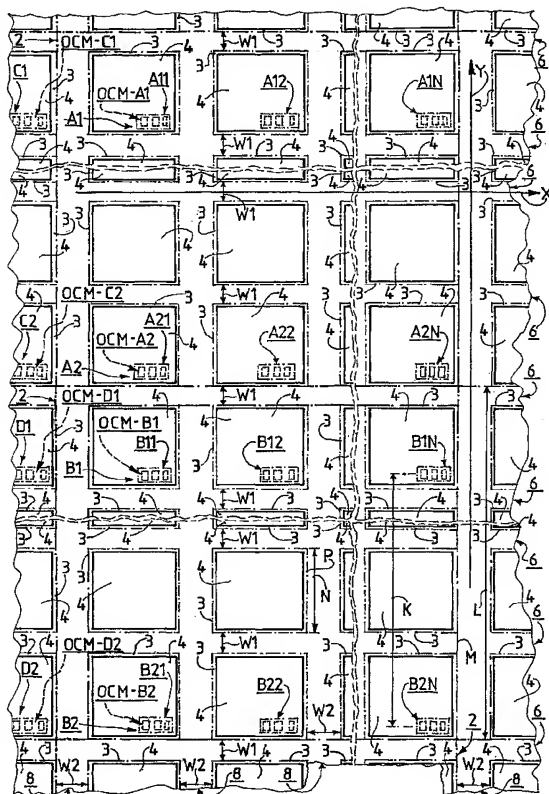
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(72) Inventor; and

(75) Inventor/Applicant (*for US only*): SCHEUCHER,
Heimo [AT/AT]; Triester Strasse 64, A-1101 Vienna (AT).

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(54) Title: WAFER WITH OPTICAL CONTROL MODULES IN IC FIELDS



(57) Abstract: In a wafer (1) with a number of exposure
fields (2), each of which exposure fields comprises a
number of lattice fields (3) with an IC (4) located therein,
two groups (5, 7) of saw paths (6, 8) are provided and two
control module fields (A1, A2, B1, B2, C1, C2, D1, D2)
are assigned to each exposure field, each of which control
module fields contains at least one optical control module
(OCM-A1, OCM-A2, OCM-B1, OCM-B2, OCM-C1,
OCM-C2, OCM-D1, OCM-D2) and lies within the exposure
field in question and comprises a plurality of control
module field sections (A11, A12..... A1N and A21,
A22..... A2N and B11, B12.....B1N and
B21, B22..... B2N and C1N and C2N and D1N and
D2N) and is distributed among several lattice grids (3),
wherein each control module field section (A11 to D2N)
is located in a lattice field and contains at least one control
module component (10,11,12,13,14,15,16,17,18).



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